

Amendments to the Claims:

1. (Original) A method for repairing line pattern defects comprising steps for:

detecting a shorting defect between a scan line and signal line and identifying the location of the defect in a flat panel display unit wherein the scan lines or signal lines or both scan lines and signal lines branch in two parts at an intersection between scan lines and signal lines, disposed with an interlayer insulation film therebetween;

cutting the portion containing the intersection between the scan line and signal line where the shorting defect is located with a laser beam; and

forming an insulation film locally at the cut to repair the shorting defect.

2. (Original) A method for repairing line defects as described in claim 1, wherein the flat panel display unit is a liquid crystal display panel.

3. (Original) A method for repairing line defects as described in claim 1, wherein the insulation film is formed locally at the cut part of locally supplying an insulation film material to the cut and heat curing the locally supplied insulation film material.

4. (Original) A method for repairing line defects comprising steps for:

detecting a shorting defect between a scan line and signal line in a flat panel display unit wherein scan lines and signal lines are formed with an interlayer insulation film therebetween;

storing the position of the detected shorting defect;

severing the scan line by emitting a laser beam to the scan line near the stored position of the shorting defect;

supplying an insulation film material locally to the area containing the severed part of the scan line; and

curing the supplied insulation film material.

5. (Original) A method for repairing line defects as described in claim 4, further comprising a step for supplying an insulation film material to the location exposed to the laser beam before the step for severing a scan line by emitting a laser beam.

6. (Original) A method for repairing line defects as described in claim 4, in which a shorting defect between a scan line and signal line is detected by applying a voltage between the scan line and signal line and locating the source of infrared detector heat produced at the short.

7. (Original) A method for repairing line defects as described in claim 4, wherein either the scan line or signal line or both bifurcate where the scan line and signal line intersect with the interlayer insulation film therebetween.

8. (Original) A method for repairing line defects comprising steps for: detecting a shorting defect between a scan line and signal line in a flat panel display unit wherein scan lines and signal lines are formed with an inter layer insulation film therebetween;

supplying insulation film material locally to an area containing a scan line where a shorting defect has occurred using the previously detected location of the shorting defect;

severing the scan line by emitting a laser beam through the insulation film material to the scan line with the shorting defect; and

forming an insulation film locally at the part severed by emitting the laser beam to the scan line.

9. (Original) A method for repairing line defects as described in claim 8, wherein either the scan line or signal line or both bifurcate where the scan line and signal line intersect with the interlayer insulation film therebetween.

10. (Original) A method for repairing line defects as described in claim 8, wherein the insulation film is formed locally at the part cut by emitting a laser beam, by locally coating the cut part with an insulation film material and heat curing the coated insulation film material.

11. (Original) A flat panel display unit having an interlayer insulation film, and a scan line and signal line disposed with an interlayer insulation film therebetween,

either the scan line or signal line or both bifurcating where the scan line and signal line intersect, wherein:

part of one of the scan lines is severed at part of the bifurcation at an intersection with the signal line, and the severed part is coated with an insulation film.

12. (Original) A flat panel display unit as described in claim 11, wherein the scan line and signal line are shorted near the severed part.

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13. (New) A method for repairing line pattern defects comprising: detecting a defect in a flat panel display unit wherein the scan lines or signal lines or both scan lines and signal lines branch in two parts at an intersection between scan lines and signal lines, the scan lines and the signal lines having an interlayer insulation film therebetween;

in either order, performing each of the following two steps to repair the defect:  
cutting the portion containing the defect with a laser beam; and  
forming an insulation film locally at the cut to repair the defect.

14. (New) A method for repairing line pattern defects in a flat panel display unit as in claim 13 wherein the defect comprises one of:

a shorting defect between a scan line and signal line; and  
an undesired foreign object situated on the flat panel display unit.

15. (New) A method as in claim 13 wherein if the step of forming an insulating film is performed first, an additional step of forming a second insulating film is performed after the step of cutting.

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